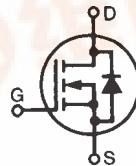




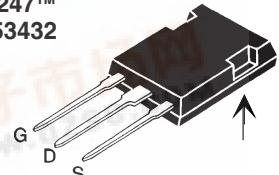
Polar™ HiPerFET Power MOSFET Electrically Isolated Tab

N-Channel Enhancement Mode
Fast Recovery Diode, Avalanche Rated



V_{DSS} = 100 V
 I_{D25} = 133 A
 $R_{DS(on)}$ = 8 mΩ

ISOPLUS 247™
E153432



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 175°C	100		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 175°C ; $R_{GS} = 1 \text{ M}\Omega$	100		V
V_{GS}		± 20		V
V_{GSM}		± 30		V
I_{D25}	$T_c = 25^\circ\text{C}$	133		A
$I_{D(RMS)}$	External lead current limit	75		A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	400		A
I_{AR}	$T_c = 25^\circ\text{C}$	60		A
E_{AR}	$T_c = 25^\circ\text{C}$	100		mJ
E_{AS}	$T_c = 25^\circ\text{C}$	4		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 4 \Omega$	10		V/ns
P_D	$T_c = 25^\circ\text{C}$	350		W
T_J		-55 ... +175		°C
T_{JM}		175		°C
T_{stg}		-55 ... +150		°C
V_{ISOL}	50/60 Hz, RMS, 1 minute	2500		V~
F_c	Mounting Force	20..120/4.6..20		Nm/lb
Weight		5		g

Symbol	Test Conditions	Characteristic Values		
	($T_J = 25^\circ\text{C}$, unless otherwise specified)	Min.	Typ.	Max.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	100		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 500 \mu\text{A}$	3.0		V
I_{GSS}	$V_{GS} = \pm 30 \text{ V}_{DC}$, $V_{DS} = 0$		± 100	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$		25	μA
		$T_J = 150^\circ\text{C}$	250	μA
	$V_{GS} = 0 \text{ V}$	$T_J = 175^\circ\text{C}$	1000	μA
	$V_{GS} = 10 \text{ V}$, $I_D = 60 \text{ A}$		8.0	$\text{m}\Omega$
	$V_{GS} = 15 \text{ V}$, $I_D = 400 \text{ A}$	5.5		$\text{m}\Omega$

Features

- Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- Low drain to tab capacitance(<30pF)
- Avalanche voltage rated
- Fast recovery intrinsic diode

Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control

Advantages

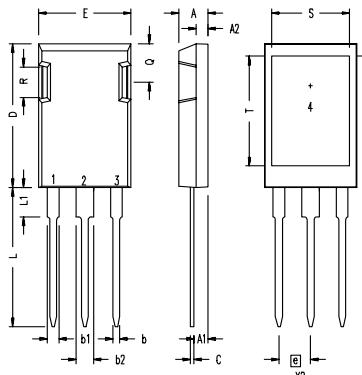
- Easy assembly
- Space savings
- High power density

Symbol **Test Conditions**
Characteristic Values
 $(T_J = 25^\circ\text{C}, \text{unless otherwise specified})$
Min. **Typ.** **Max.**

g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 100 \text{ A}$, Note 1	60	97	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	7600	pF	
		2900	pF	
		860	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 60 \text{ A}$ $R_G = 3.3 \Omega$ (External)	30	ns	
		35	ns	
		150	ns	
		90	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 100 \text{ A}$	240	nC	
		50	nC	
		135	nC	
R_{thJC}			.42	K/W
R_{thCK}		0.15		K/W

Source-Drain Diode
Characteristic Values
 $(T_J = 25^\circ\text{C}, \text{unless otherwise specified})$
Symbol **Test Conditions**
Min. **typ.** **Max.**

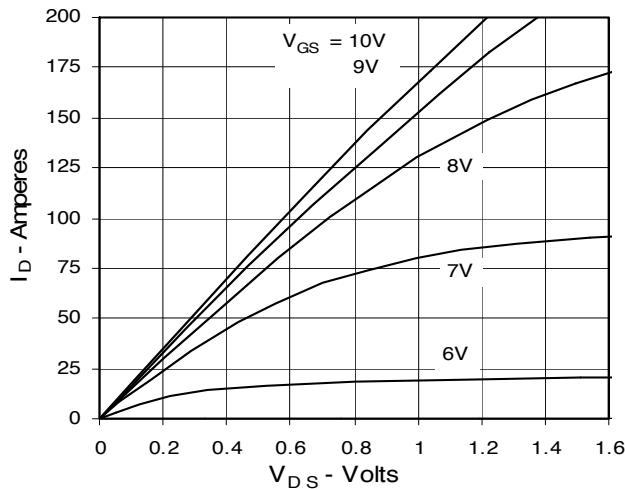
I_s	$V_{GS} = 0 \text{ V}$		200	A
I_{SM}	Repetitive		400	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Note 1		1.5	V
t_{rr}	$I_F = 25 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$	100	140	ns

ISOPLUS 247 OUTLINE


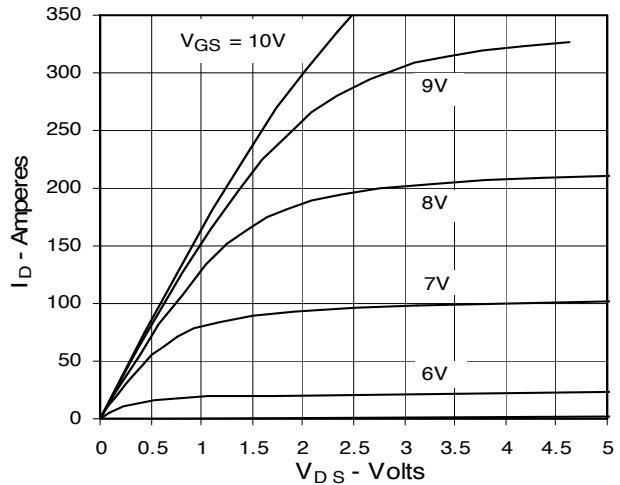
Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	.190	.205
A ₁	2.29	2.54	.090	.100
A ₂	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b ₁	1.91	2.13	.075	.084
b ₂	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45	BSC	.215	BSC
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190

Notes: 1. Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2\%$

**Fig. 1. Output Characteristics
@ 25°C**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 3. Output Characteristics
@ 150°C**

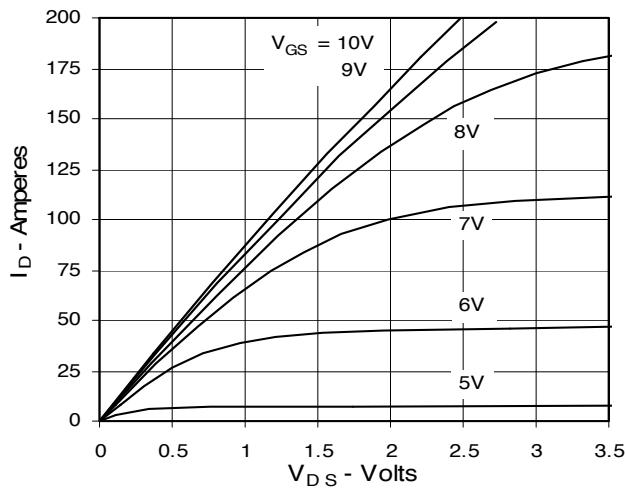


Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Drain Current

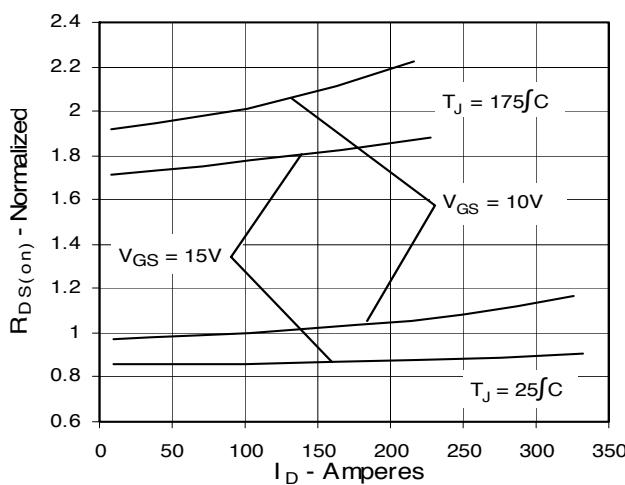


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature

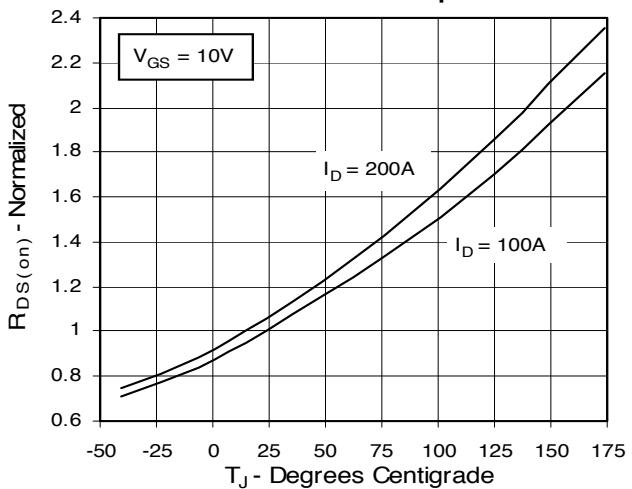


Fig. 6. Drain Current vs. Case Temperature

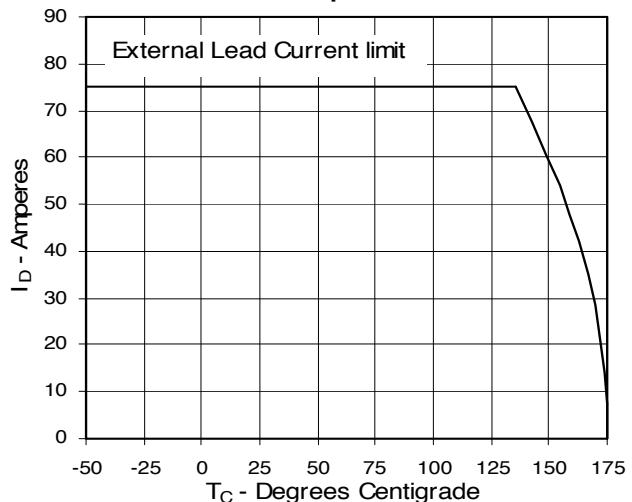
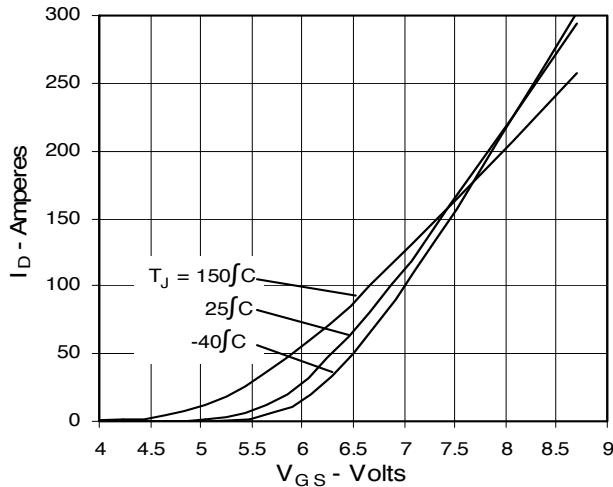


Fig. 7. Input Admittance



**Fig. 9. Source Current vs.
Source-To-Drain Voltage**

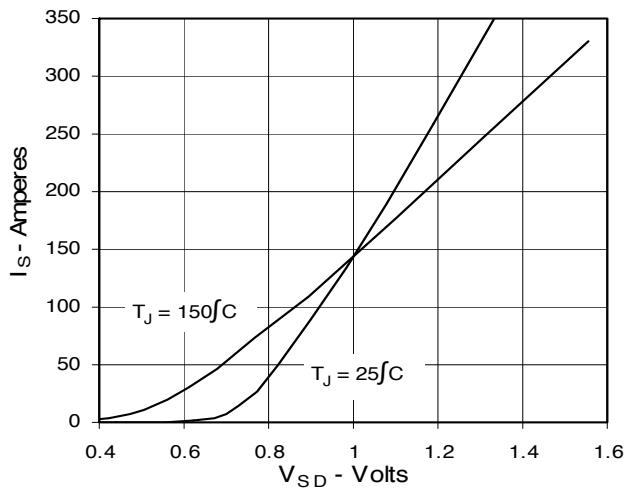


Fig. 11. Capacitance

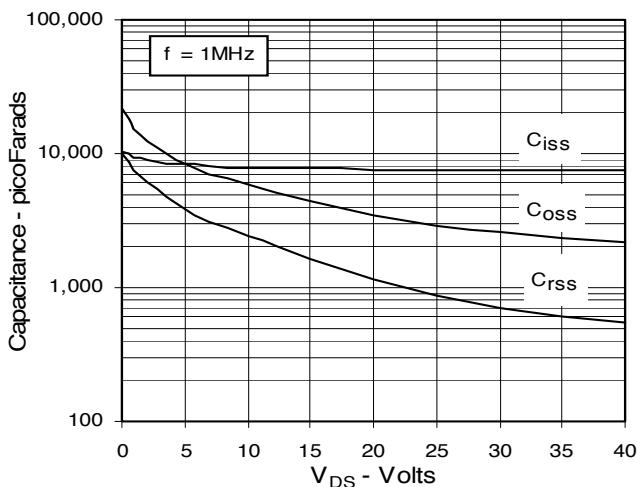


Fig. 8. Transconductance

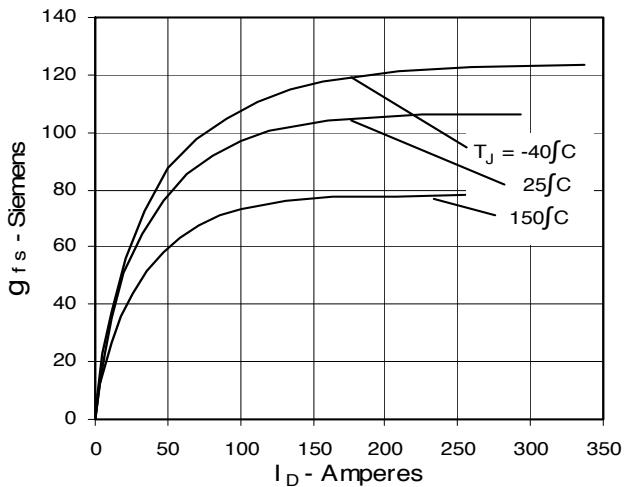
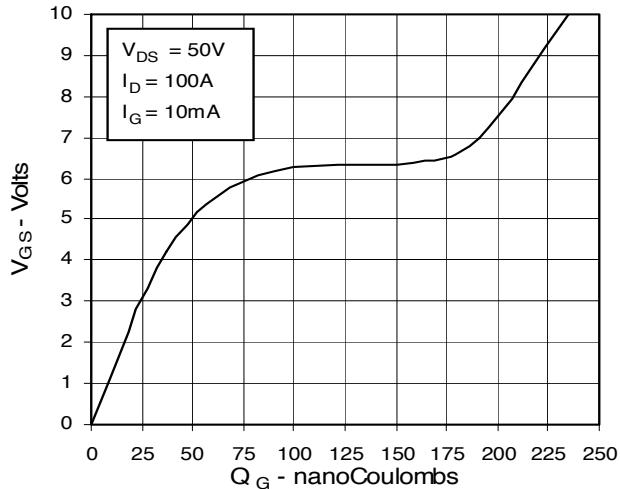


Fig. 10. Gate Charge



**Fig. 12. Forward-Bias
Safe Operating Area**

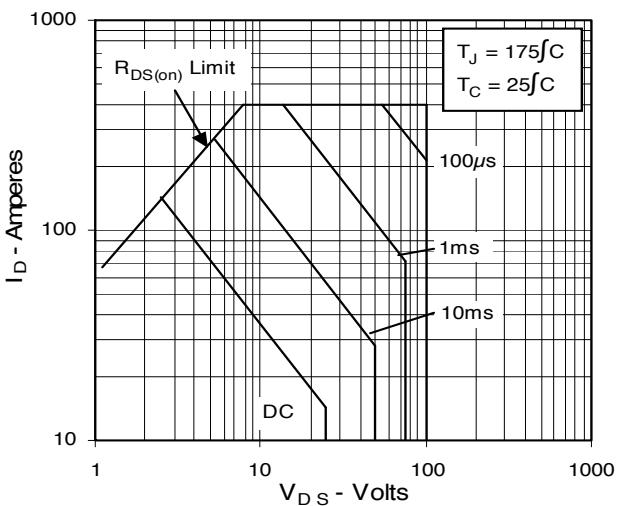


Fig. 13. Maximum Transient Thermal Resistance